PCN Number:			20	141	119000A							<b>PCN Date:</b> 01/20/2015			
Titl	Title: Qualification of ASE Shanghai as an alternate Assembly/Test Site for Selected devices in the TSSOP Package									ed devices in					
Cus	tome	er Contact:	PCN Manager		<u>nager</u>	Ph	none:	ne:				Dept:		ality rvices	
Pro	pose	d 1 <sup>st</sup> Ship Da	te:	0	D3/03/2015 Estimated Sample A			le A	Availability: Provided upon Request						
		Туре:													
$\boxtimes$		mbly Site		<u> </u>	Assembly Process						Assembly Materials				
	Desi			<u> </u>	Electrical S					Ц		lechanical Specification			
	Test			<u> </u>	Packing/Sh					<u>Ц</u>		t Process			
		er Bump Site		<u> </u>	Wafer Bum	•				<u>Ц</u>		er Bump			
Ш	ware	er Fab Site		<u> </u>	Wafer Fab						ware	er Fab Pr	oces	S	
					Part number										
Door		ion of Chang				<u> </u>	N De	talis							
site finis Tex alte add	Revision A is to update the BOM differences as a result of adding ASEH as an additional assembly site for the listed devices in Group 1. ASESH will be manufacturing devices with Matte Sn lead finish. These modifications are highlighted and <b>bolded</b> below.  Texas Instruments is pleased to announce the qualification of ASE Shanghai (ASES) as an alternate Assembly and Test site for the devices listed below in Group 1 and TI Taiwan (TAI) as an additional Assembly site for the devices in Group 2. Group 2 devices will have identical BOMs between the 2 sites. For group 1, BOM differences are noted in the table below:														
	Wha	it			MLA			Α	P1				ASE	SH	
Mold Compound 4206193 SID# 101325962					SID#EN2000508										
Mound Compound			4042500				SID#101306338			8	SID#EY1000063				
Lead FinishNiPdAuNiPdAuMatte Sn							e Sn								
Test coverage, insertions, conditions will remain consistent with current testing and verified with test MQ.  Upon expiry of this PCN TI will combine lead free solutions in a single <u>standard part number</u> , for example; <u>AM26C31IPWR</u> – can ship with both Matte Sn and NiPdAu/Ag.															
Exa	mple		er o	rde	er for 7500	<mark>un</mark> i	its of <i>i</i>	AM26C3	31II	PWI	R witl	h 2500	<mark>unit</mark> s	s SPQ	

- (Standard Pack Quantity per Reel).
- TI can satisfy the above order in one of the following ways.
  - I. 3 Reels of NiPdAu finish.
  - 3 Reels of Matte Sn finish II.
  - III. 2 Reels of Matte Sn and 1 reel of NiPdAu finish.
  - IV. 2 Reels of NiPdAu and 1 reel of Matte Sn finish.

# **Reason for Change:**

Continuity of Supply

Anticipated impact on Fit, Form, Function, Quality or Reliability (positive / negative):

None

Changes to product identification resulting from this PCN:							
Assembly Site							
Amkor Philippines	Assembly Site Origin (22L)	ASO: AKR					
TI Malaysia	Assembly Site Origin (22L)	ASO: MLA					
TI Taiwan	Assembly Site Origin (22L)	ASO: TAI					
ASE Shanghai	Assembly Site Origin (22L)	ASO: ASH					
Texas Instruments  MADE IN: Malaysia  2DC:  MSL '2 /260C/1 YEAR SEAL DT  MSL 1 /235C/UNLIM 03/29/04  OPT:  ITEM:  ITEM:  JOPT:  JOPT:							
Assembly site code for AKR= 4 Assembly site code for MLA= K Assembly site code for TAI= T Assembly site code for ASH= A	Topside Device marking: Assembly site code for AKR= 4 Assembly site code for MLA= K  Assembly site code for TAI= T  G4 = NiPdAu G3= MATTE Sn						

# **Product Affected**

Qualification Group #1 Devices (ASESH assembly):

AM26C31IPWR	MAX3232IPWR	SN74HC125PWR	SN74HC32PWR	
CD4066BPWR	SN74ACT08PWR	SN74HC138PWR	SN74HC595PWR	
CD4069UBPWR	SN74AHCT125PWR	SN74HC14PWR	SN74HCT04PWR	
CD4541BPWR	SN74HC00PWR	SN74HC164PWR	SN74HCT138PWR	
CD74HC123PWR	SN74HC02PWR	SN74HC166PWR	SN74HCT14PWR	
LM239PWR	SN74HC04PWR	SN74HC174PWR	SN74HCT32PWR	
LM339APWR	SN74HC05PWR	SN74HC259PWR	SN74HCU04PWR	
MAX232FCPWR	SN74HC08PWR			

# **Qualification Group #2 Devices (TAI assembly):**

DRV8833PWP DRV8833PWPR

# **Qualification Group #1 Data:**

### Qualification Report

## MAX232ECPWR Qual (ASESH 14 and 16 pins TSSOP Offload) Approved 09/22/2014

Attributes	Qual Device: MAX232ECPWR	QBS Package: RC4558PWR	QB S Package: SN74LV14APWR	QBS Package: SN74LVC14APWR	QBS Package: ULN2003APW	QBS Package: LMV324IPWR	QB S Package: SN74AHC595PWR	QBS Package: SN74CBT3306PWR	QBS Package: SN74CBTLV3245APWR
Assembly Site	ASESH	ASE SHANGHAI	ASESH	ASE-SH	ASESH	ASE SHANGHAI	ASE SHANGHAI	ASE SHANGHAI	ASE SHANGHAI
Package Family	TSSOP	TSSOP	TSSOP	TSSOP	TSSOP	TSSOP	TSSOP	TSSOP	TSSOP
Flammability Rating	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0
Wafer Fab Supplier	DFAB	SFAB	SFAB	FFAB	SFAB	FFAB	SFAB	SFAB	FFAB
Wafer Fab Process	LBC3S	JI-SLM	EPIC1-S_SLM	P-9750 TLM	JI-SLM	BCB	EPIC1S DLM	50C24X2	ASL3C

## Qualification Results

<b>!</b> •				Da	ata Displayed as: Number	of lots / Total sample :	size / Total failed			
Туре	Test Name / Condition	Duration	QBS Package: RC4558PWR	QBS Package: SN74LV14APWR	QBS Package: SN74LVC14APWR	QBS Package: ULN2003APW	QBS Package: LMV324IPWR	QBS Package: SN74AHC595PWR	QBS Package: SN74CBT3306PWR	QBS Package: SN74CBTLV3245APWR
HAST	Biased HAST, 130C/85%RH	96 Hours	1/77/0	1/77/0	1/77/0	1/77/0	2/158/0	1/77/0	1/77/0	1/77/0
THB	Temperature Humidity Bias 85C/85%RH	1000 Cycles	•	•	-	•	-	-	-	-
AC	Autoclave 121C	96 Hours	-		-	-	-	-	-	-
UHAST	Unbiased HAST 130C/85%RH	96 Hours	1/77/0	1/77/0	1/77/0	1/77/0	1/77/0	1/77/0	1/77/0	1/77/0
TC	Temperature Cycle, - 65/150C	500 Cycles	1/77/0	1/77/0	1/77/0	1/77/0	1/77/0	1/77/0	1/77/0	1/77/0
HTSL	High Temp. Storage Bake 170C	420 Hours	-	-	-	-	1/77/0	1/77/0	1/77/0	1/77/0
HTSL	High Temp. Storage Bake 150C	1000 Hours	1/77/0	1/77/0	1/77/0	1/77/0	-	-	-	-
HTOL	Life Test, 150C	300 hours	1/77/0	1/77/0	1/77/0	1/77/0	2/164/0	1/77/0	1/77/0	1/77/0
WBS	Ball Bond Shear	Wires	-	-	-	-	-	-	-	-
WBP	Bond Pull	Wires	-	-	-	-	-	-	-	-
PD	Physical Dimensions	-	-		-	-	-			-
HBM	ESD - HBM	1000 V	-		-	-	-			-
CDM	ESD - CDM	250 V	-	•	-	•	-	•	•	•
LU	CMOS Latchup	(per JESD78 class II)	-	•	-	-	-	-	-	-
ED	Electrical Characterization	Per Datasheet Parameters	Pass	Pass	Pass	Pass	Pass	Pass	Pass	Pass
	Bond Strength	Wires	1/76/0	1/76/0	1/76/0	1/76/0	2/160/0	1/77/0	1/77/0	1/77/0

## Qualification Group #2 Data:

#### Reference Qualification Data: Approved April 2012 This qualification has been specifically developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications. **Qualification Device: DRV8812A1PWP** (MSL1-260C) **Package Construction Details** Assembly Site: TAI A/T Mold Compound: 4205443 # Pins-Designator, Family: 28-PWP, TSSOP Mount Compound: 4208458 Lead Frame Material/Finish: Cu, NiPdAu Bond Wire: 1.3 Mil Dia., Cu Qualification: Plan Test Results Reliability Test Conditions Sample Size / Fail Electrical Characterization Per Datasheet Limits **Pass** 77/0 \*\*Autoclave 121C 121C, 2 atm (96 Hrs) 77/0 \*\*T/C -65C/150C -65C/+150C (500 Cyc) 3/0 ESD HBM 500V, 1000V, 1500V 200V, 500V 3/0 ESD CDM 6/0 Latch-up (per JESD78) Notes: \*\*Tests require preconditioning sequence: MSL1-260C

OBS: Qual By Similarity
 Qual Device MAX232ECPWR is qualified at LEVEL1-260C

Preconditioning was performed for Autoclave, Unbiased HAST, THBIBiased HAST, Temperature Cycle, Thermal Shook, and HTSL, as applicable The following are equivalent HTOL options based on an activation energy of 0.7eV: 1250/1k Hours, 1400/480 Hours, 1500/300 Hours, and 1550/240 Hours The following are equivalent HTOL options based on an activation energy of 0.7eV: 1500/1k Hours, and 1700/420 Hours The following are equivalent Temp Cycle options per JESD47: -850/1250/700 Cycles and 4700/420 Hours Shoot Shoot

Quality and Environmental data is Green/Pb-free Status: Qualified Pb-Free(SMT) and Green

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

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Europe	PCNEuropeContact@list.ti.com
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